Source	$\mathcal{B}(\mathrm{B}^0_\mathrm{s} \to \mu^+\mu^-)$ [%]	$\tau_{\mu^+\mu^-}$ [ps]	
		2D UML	*sPlot*
Kaon tracking	2.3–4	—	—
Normalization yield	4	—	—
Background yields	1	0.03	(*)
Production process	3	—	—
Muon identification	3	—	—
Trigger	3	—	—
Efficiency (data/MC simulation)	5–10	—	(*)
Efficiency (functional form)	—	0.01	0.04
Efficiency lifetime dependence	1–3	(*)	(*)
Era dependence	5–6	0.07	0.07
BDT discriminator threshold	—	0.02	0.02
Silicon tracker alignment	—	0.02	—
Finite size of MC sample	—	0.03	—
Fit bias	—	—	0.09
$\mathcal{C}$-correction	—	0.01	0.01
Total systematic uncertainty	$(^{+0.3}_{-0.2}) \times 10^{-9}$	0.09	0.12
Total uncertainty	$(^{+0.7}_{-0.6}) \times 10^{-9}$	$^{+0.61}_{-0.44}$	$^{+0.52}_{-0.33}$